

Description

The AP4406A uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a

Battery protection or in other Switching application.



 $V_{DS} = 30V I_{D} = 12A$

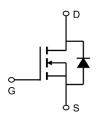
 $R_{DS(ON)}$ < 12m Ω @ V_{GS} =10V

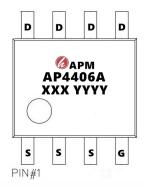
Application

Battery protection

Load switch

Uninterruptible power supply







Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP4406A	SOP-8	AP4406A XXX YYYY	3000

Absolute Maximum Ratings (T_c=25 ℃ unless otherwise noted)

Symbol	Parameter	Max.	Units		
VDSS	Drain-Source Voltage	30	V		
VGSS	Gate-Source Voltage	±20	V		
I _D @T _A =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	12	А		
ID@T _A =70°C	Continuous Drain Current, V _{GS} @ 10V ¹	8	А		
Ірм	Pulsed Drain Current note1	ılsed Drain Current ^{note1} 48			
Eas	Single Pulsed Avalanche Energy note2	16	mJ		
P _D @T _A =25°C	Total Power Dissipation ⁴	3	W		
Rеја	Thermal Resistance, Junction to Ambient	46	°C/W		
Tı, Tstg	Operating and Storage Temperature Range	-55 to +150	$^{\circ}$		





Electrical Characteristics (T_J=25°C, unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	30	33	-	V
IDSS	Zero Gate Voltage Drain Current	V _{DS} =30V, V _{GS} =0V,	-	-	1.0	μΑ
IGSS	Gate to Body Leakage Current	V _{DS} =0V, V _{GS} =±20V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250µA	1.2	1.6	2.5	V
RDS(on)	Static Drain-Source on-Resistance note3	V _{GS} =10V, I _D =13A	-	8.5	12	mΩ
RDS(on)	Static Drain-Source on-Resistance note3	V _{GS} =4.5V, I _D =10A	-	13	18	
Ciss	Input Capacitance		-	900	-	pF
Coss	Output Capacitance	V _{DS} =15V, V _{GS} =0V, f=1.0MHz	-	140	-	pF
Crss	Reverse Transfer Capacitance		-	120	-	pF
Qg	Total Gate Charge		-	19	-	nC
Qgs	Gate-Source Charge	V_{DS} =15V, I_{D} =10A, V_{GS} =10V	-	6.3	-	nC
Q _{gd}	Gate-Drain("Miller") Charge		-	4.5	-	nC
td(on)	Turn-on Delay Time		-	6	-	ns
t _r	Turn-on Rise Time	V_{DS} =15V, I_{D} =6A, R_{GEN} =3 Ω ,	-	5	-	ns
td(off)	Turn-off Delay Time	V _{GS} =10V	-	25	-	ns
t _f	Turn-off Fall Time		-	7	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	12	Α
ISM	Maximum Pulsed Drain to Source Diode Forward Current		-	-	48	Α
VSD	Drain to Source Diode Forward Voltage	V _{GS} =0V, I _S =12A	-	-	1.2	V
trr	Body Diode Reverse Recovery Time		-	7	-	ns
Qrr	Body Diode Reverse Recovery Charge	I _F =10A,dI/dt=100A/μs	-	6.3	-	nC

Note:

- 1. The data tested by surface mounted on a 1 inch FR-4 board with 2OZ copper.
- 2 The data tested by pulsed , Pulse Width≤300µs, Duty Cycle≤0.5%
- 3. The EAS data shows Max. rating . The test condition is $T_J=25^{\circ}C$, $V_{GS}=10V$, $R_G=25\Omega$, L=0.5mH, $I_{AS}=8A$
- 4. The power dissipation is limited by 150 $^{\circ}\mathrm{C}$ junction temperature
- 5 The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.



Typical Characteristics

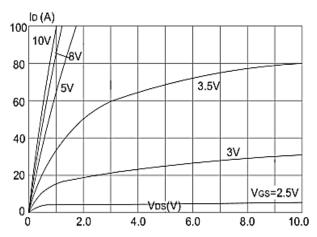


Figure1: Output Characteristics

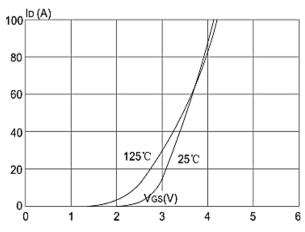


Figure 2: Typical Transfer Characteristics

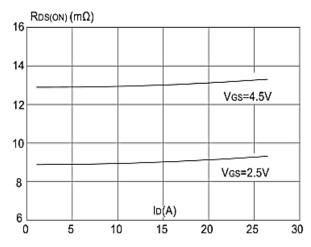


Figure 3:On-resistance vs. Drain Current

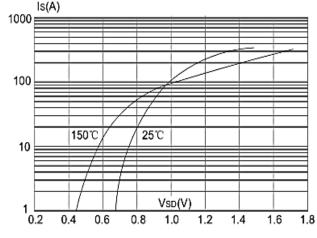


Figure 4: Body Diode Characteristics

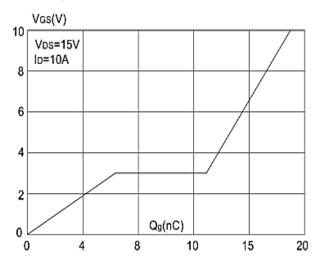


Figure 5: Gate Charge Characteristics

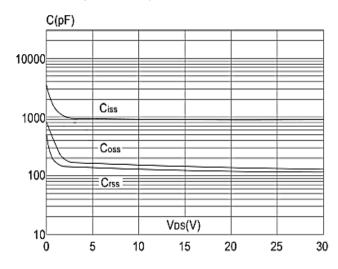


Figure 6: Capacitance Characteristics





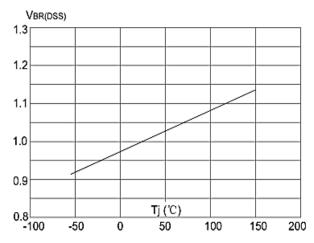


Figure 7: Normalized Breakdown Voltage vs Junction Temperature

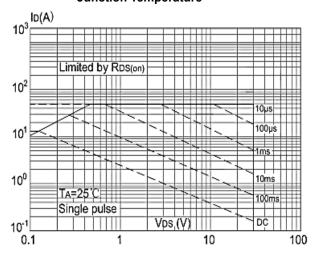


Figure 9: Maximum Safe Operating Area

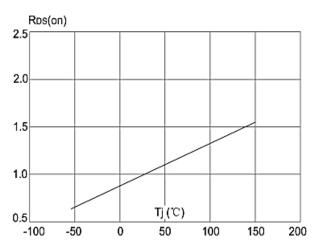


Figure 8: Normalized on Resistance vs.

Junction Temperature

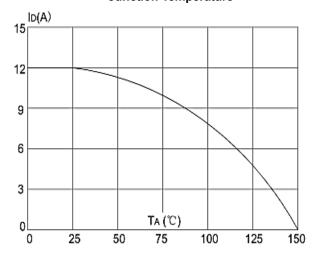


Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

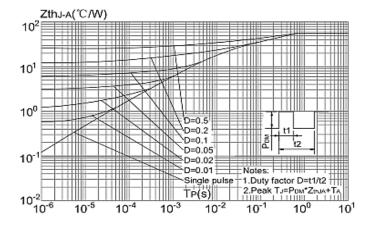
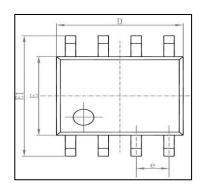
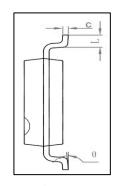


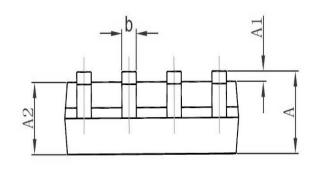
Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Ambien



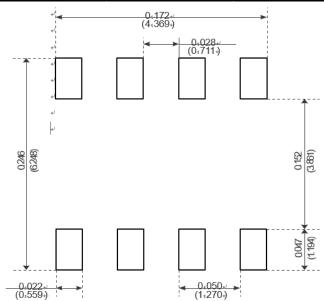
Package Mechanical Data-SOP-8







CI	Dimensions In Millimeters		Dimensions In Inches		
Symbol	Min	Max	Min	Max	
Α	1. 350	1. 750	0. 053	0.069	
A1	0. 100	0. 250	0. 004	0. 010	
A2	1. 350	1. 550	0. 053	0. 061	
b	0. 330	0. 510	0. 013	0. 020	
С	0. 170	0. 250	0.006	0. 010	
D	4. 700	5. 100	0. 185	0. 200	
E	3. 800	4. 000	0. 150	0. 157	
E1	5. 800	6. 200	0. 228	0. 244	
е	1. 270 (BSC)		0. 050 (BSC)		
L	0. 400	1. 270	0. 016	0. 050	
θ	0°	8°	0°	8°	



Recommended Minimum Pads-



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